Support Information

Enhanced film quality of PbS QD solid by Eliminating the oxide

traps through an in-situ surface etching and passivation

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Figure S1 (A) Cross-sectional image of the pristine PbS/ZnS film, (B) elemental mapping of PbS/ZnS film in the rectangular area in (A), (C,D) top view SEM images of PbS/ZnS film before (C) and after (D) I^-/I_2 treatment.

cell	Treatmen t	$J_{\rm SC}$ (mA.cm ⁻²)	$V_{\rm OC}({ m mV})$	FF	η(%)
1	N	19.73	378	0.535	3.96
	Т	21.17	418	0.536	4.71
2	Ν	19.26	382	0.542	3.92
	Т	21.04	428	0.533	4.77
3	Ν	19.89	392	0.524	4.01
	Т	22.2	422	0.511	4.7
4	Ν	19.77	393	0.528	4.02
	Т	22.29	423	0.519	4.8
5	Ν	18.84	386	0.551	4
	Т	21.35	421	0.544	4.82
Averag	N	19.50±0.66	386±8	0.536±0.02	3.98±0.06
e	Т	21.61±0.68	422±6	0.529±0.02	4.76±0.06

Table S. Photovoltaic parameters and their average with standard deviation of five PbS QDSSCs with (T) and without (N) I^-/I_2 treatment.



Figure S2. J-V curves of CdS (A) and CdS/CdSe (B) sensitized QDSSCs without (a)

and with (b) I^-/I_2 treatment.



Figure S3. Short circuit photocurrent density of QDSSC of TiO₂/PbS with and without

 I^{-}/I_{2} treatment as a function of time using periodic illumination intervals.